

WEST Search History

DATE: Friday, April 16, 2004

<u>Hide?</u>	<u>Set</u>	<u>Query</u>	<u>Hit Count</u>
<i>DB=PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD; PLUR=YES; OP=ADJ</i>			
<input type="checkbox"/>	L12	L11 and color	38
<input type="checkbox"/>	L11	L10 and mark\$	85
<input type="checkbox"/>	L10	L9 and analyz\$	147
<input type="checkbox"/>	L9	L6 and type	223
<input type="checkbox"/>	L8	L6 and type of defect	0
<input type="checkbox"/>	L7	L6 and inspection instrument	5
<input type="checkbox"/>	L6	L5 and wafer map	265
<input type="checkbox"/>	L5	defect with wafer	13587
<input type="checkbox"/>	L4	semiconductor defect inspection	29
<input type="checkbox"/>	L3	semiconductor defect inspection instrument	2
<input type="checkbox"/>	L2	5659172.pn. or 5985497.pn. or 6051845.pn. or 6122562.pn. or 6246787.pn. or 6252412.pn. or 6265232.pn. or 6407373.pn. or 6441897.pn.	18
<input type="checkbox"/>	L1	("6524881" "6559457" "20030003688A1").PN.	4

END OF SEARCH HISTORY